# Binary to 1-8 Decoder (High)

The MC10162 is designed to convert three lines of input data to a one–of–eight output. The selected output will be high while all other outputs are low. The enable inputs, when either or both are high, force all outputs low.

The MC10162 is a true parallel decoder. No series gating is used internally, eliminating unequal delay times found in other decoders.

This device is ideally suited for demultiplexer applications. One of the two enable inputs is used as the data input, while the other is used as a data enable input.

A complete mux/demux operation on 16 bits for data distribution is illustrated in Figure 1 of the MC10161 data sheet.

- $P_D = 315 \text{ ns typ/pkg (No Load)}$
- $t_{pd} = 4.0 \text{ ns typ}$
- $t_r$ ,  $t_f = 2.0$  ns typ (20%–80%)

# E0 2 E1 15 A 7 B 9 V<sub>CC1</sub> = PIN 1 V<sub>CC2</sub> = PIN 16 V<sub>EE</sub> = PIN 8

### **TRUTH TABLE**

INPUTS								OUTF	PUTS			
Ē0	<del>E</del> 1	C	В	Α	Q0	Q1	Q2	Q3	Q4	Q5	Q6	Q7
L	L	L	L	L	H	L	L	L	L	L	L	L
L	L	L	L	Н	L	Н	L	L	L	L	L	L
L	L	L	Н		L	L	Н	L	L	L	L	L
L	L	L	н	Н	L	L	L	Н	L	L	L	L
L	L	Н	L	L	L	L	L	L	Н	L	L	L
L	L	H	L	Н	L	L	L	L	L	Н	L	L
L	L A	Н	Н	L	L	L	L	L	L	L	Н	L
L	L	Н	Н	Н	L	L	L	L	L	L	L	Н
Н	X	X	Χ	Х	L	L	L	L	L	L	L	L
X	Н	Χ	Χ	Χ	L	L	L	L	L	L	L	L



### ON Semiconductor

http://onsemi.com

## MARKING DIAGRAMS



CDIP-16 L SUFFIX CASE 620 16 DDDDDDDD MC10162L AWLYYWW DDDDDDDDD



PDIP-16 P SUFFIX CASE 648





PLCC-20 FN SUFFIX CASE 775



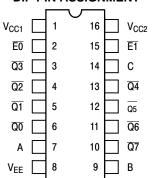
A = Assembly Location

WL = Wafer Lot

YY = Year

WW = Work Week

### **DIP PIN ASSIGNMENT**



Pin assignment is for Dual-in-Line Package.
For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).

### **ORDERING INFORMATION**

Device	Package	Shipping
MC10162L	CDIP-16	25 Units / Rail
MC10162P	PDIP-16	25 Units / Rail
MC10162FN	PLCC-20	46 Units / Rail

### MC10162

### **ELECTRICAL CHARACTERISTICS**

							Test Limits	3			
			Pin Under	-30	0∘C		+25°C		+85	5°C	1
Characteristic		Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply	Drain Current	Ι <sub>Ε</sub>	8		84		61	76		84	mAdc
Input Current		I <sub>inH</sub>	14		350			220		220	μAdc
		I <sub>inL</sub>	14	0.5		0.5			0.3		μAdc
Output Voltag	e Logic 1	V <sub>OH</sub>	13	-1.060	-0.890	-0.960		-0.810	-0.890	-0.700	Vdc
Output Voltag	e Logic 0	V <sub>OL</sub>	13 13	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
Threshold Vol	Itage Logic 1	V <sub>OHA</sub>	13	-1.080		-0.980			-0.910		Vdc
Threshold Vol	ltage Logic 0	V <sub>OLA</sub>	13 13		-1.655 -1.655			-1.630 -1.630		-1.595 -1.595	Vdc
Switching Tim	nes (50Ω Load)										ns
Propagation D	Delay	t <sub>14+13-</sub> t <sub>14–13+</sub>	13 13	1.5 1.5	6.2 6.2	1.5 1.5	4.0 4.0	6.0 6.0	1.5 1.5	6.4	
Rise Time	(20 to 80%)	t <sub>13+</sub>	13	1.0	3.3	1.1	2.0	3.3	1.1	3.5	
Fall Time	(20 to 80%)	t <sub>13-</sub>	13	1.0	3.3	1.1	2.0	3.3	1.1	3.5	

### **ELECTRICAL CHARACTERISTICS** (continued)

ELECTRICAL CHAR		(	,						
TEST VOLTAGE VALUES (\									
	V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>EE</sub>				
			–30°C	-0.890	-1.890	-1.205	-1.500	-5.2	
			+25°C	-0.810	-1.850	-1.105	-1.475	-5.2	
			+85°C	-0.700	-1.825	-1.035	-1.440	-5.2	
			Pin	TEST VC	LTAGE APF	LIED TO PII	NS LISTED B	ELOW	
Characterist	ic	Symbol	Under Test	V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>EE</sub>	(V <sub>CC</sub> ) Gnd
Power Supply Drain Cu	ırrent	IE.	8					8	1,16
Input Current		l <sub>inH</sub>	14	14				8	1,16
		l <sub>inL</sub>	14		14			8	1,16
Output Voltage	Logic 1	V <sub>OH</sub>	13	14				8	1,16
Output Voltage	Logic 0	V <sub>OL</sub>	13 13	2 15				8 8	1,16 1,16
Threshold Voltage	Logic 1	V <sub>OHA</sub>	13	13		14		8	1,16
Threshold Voltage	Logic 0	V <sub>OLA</sub>	13 13			2 15		8 8	1,16 1,16
Switching Times	(50Ω Load)					Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	1	t <sub>14+13+</sub> t <sub>14–13</sub>	13 13			14 14	13 13	8 8	1,16 1,16
Rise Time	(20 to 80%)	t+	13			14	13	8	1,16
Fall Time	(20 to 80%)	t–	13			14	13	8	1,16

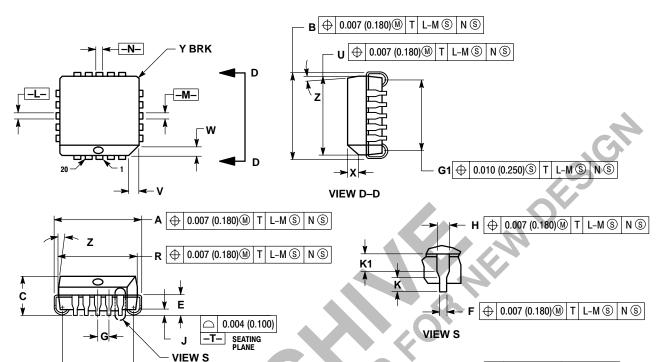
Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

### MC10162

### PACKAGE DIMENSIONS

### PLCC-20 **FN SUFFIX**

PLASTIC PLCC PACKAGE CASE 775-02 ISSUE C



### NOTES:

G1 ⊕ 0.010 (0.250)③ T L-M ⑤ N ⑤

OF VICE NOT PRESCO

- IOTES:

  1. DATUMS -L-, -M-, AND -N- DETERMINED WHERE TOP OF LEAD SHOULDER EXITS PLASTIC BODY AT MOLD PARTING LINE.

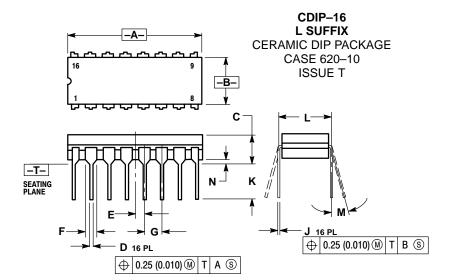
  2. DIMENSION G1, TRUE POSITION TO BE MEASURED AT DATUM -T-, SEATING PLANE.

  3. DIMENSIONS R AND U DO NOT INCLUDE MOLD FLASH. ALLOWABLE MOLD FLASH IS 0.010 (0.250) PER SIDE.

  4. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M. 1982.
- Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO 0.012 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
- DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

	INC	HES	MILLIM	ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.385	0.395	9.78	10.03
В	0.385	0.395	9.78	10.03
С	0.165	0.180	4.20	4.57
Ε	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050	BSC	1.27	BSC
Н	0.026	0.032	0.66	0.81
J	0.020		0.51	
K	0.025		0.64	
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
٧	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
Х	0.042	0.056	1.07	1.42
Υ		0.020		0.50
Z	2 °	10°	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040		1.02	

### MC10162



### NOTES:

- ANIES.

  DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

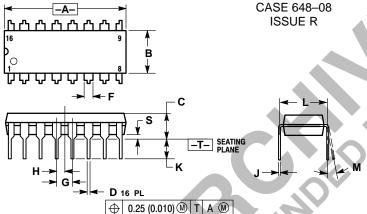
  CONTROLLING DIMENSION: INCH.

  DIMENSION L TO CENTER OF LEAD WHEN

- FORMED PARALLEL.
  DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC

	INC	HES	MILLIMETERS			
DIM	MIN	MAX	MIN	MAX		
Α	0.750	0.785	19.05	19.93		
В	0.240	0.295	6.10	7.49		
С		0.200		5.08		
D	0.015	0.020	0.39	0.50		
E	0.050	BSC	1.27 BSC			
F	0.055	0.065	1.40	1.65		
G	0.100	BSC	2.54 BSC			
Н	0.008	0.015	0.21	0.38		
K	0.125	0.170	3.18	4.31		
L	0.300	BSC	7.62 BSC			
М	0°	15°	0 °	15°		
N	0.020	0.040	0.51	1.01		





- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
- DIMENSION B DOES NOT INCLUDE MOLD FLASH.
  ROUNDED CORNERS OPTIONAL

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27 BSC		
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
M	0°	10°	0 °	10 °	
S	0.020	0.040	0.51	1.01	

ON Semiconductor and War are trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer.

### PUBLICATION ORDERING INFORMATION

### Literature Fulfillment:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada

Email: ONlit@hibbertco.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

JAPAN: ON Semiconductor, Japan Customer Focus Center 4-32-1 Nishi-Gotanda, Shinagawa-ku, Tokyo, Japan 141-0031

Phone: 81-3-5740-2700 Email: r14525@onsemi.com

ON Semiconductor Website: http://onsemi.com

For additional information, please contact your local Sales Representative.